

GANGRENE: Exploring the Mortality of Flash Memory

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When evaluating the lifetime of Flash memory the industry currently uses an *average* workload to derive a bound on the number of writes that the device can support. This paper shows that a *malicious* work load can greatly reduce Flash lifetime. The reviewers found this aspect of the work interesting, especially since it suggests changing how Flash lifetime is measured. However, all the reviewers agreed that the defense section of the paper is somewhat weak and should be improved if possible. In particular, defense strategies should be discussed in greater depth and hopefully more defenses can be added. Despite the complaints about the defense section there was agreement that this is a good contribution to the workshop and will likely generate some discussion on how to best address this attack.